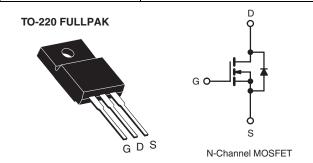


Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	250	250			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	1.1			
Q _g (Max.) (nC)	14				
Q _{gs} (nC)	2.7	2.7			
Q _{gd} (nC)	7.8	7.8			
Configuration	Sing	Single			



FEATURES

- · Isolated Package
- High Voltage Isolation = 2.5 kV_{RMS} (t = 60 s; f = 60 Hz)



RoHS'

- Sink to Lead Creepage Distance = 4.8 mm
- Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 FULLPAK eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The FULLPAK is mounted to a heatsink using a single clip or by a single screw fixing.

ORDERING INFORMATION			
Package	TO-220 FULLPAK		
Lead (Pb)-free	IRFI624GPbF		
Leau (Fb)-liee	SiHFI624G-E3		
SnPb	IRFI624G		
SILL	SiHFI624G		

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	250	V	
Gate-Source Voltage			V_{GS}	± 20	1 v	
Continuous Drain Current	V _{GS} at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	I-	3.4		
		T _C = 100 °C	ID	2.2	Α	
Pulsed Drain Current ^a			I _{DM}	14		
Linear Derating Factor				0.24	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	100	mJ	
Repetitive Avalanche Current ^a			I _{AR}	3.4	Α	
Repetitive Avalanche Energy ^a			E _{AR}	3.0	mJ	
Maximum Power Dissipation	T _C = 25 °C		P_{D}	30	W	
Peak Diode Recovery dV/dtc			dV/dt	4.8	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		·	300 ^d		
Mounting Torque	6 22 or N	6-32 or M3 screw		10	lbf ⋅ in	
	0-32 OF M3 SCIEW			1.1	N⋅m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 13 mH, R_G = 25 Ω , I_{AS} = 3.4 A (see fig. 12).
- c. $I_{SD} \le 4.4$ A, $dI/dt \le 90$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFI624G, SiHFI624G

Vishay Siliconix



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	4.1	C/VV	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static		•					
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	250	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	-	0.36	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zaus Osta Valtana Dusin Osumat		V _{DS} =	V _{DS} = 250 V, V _{GS} = 0 V		-	25	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 200 \	V _{DS} = 200 V, V _{GS} = 0 V, T _J = 125 °C		-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.0 A ^b	-	-	1.1	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	= 50 V, I _D = 2.0 A ^b	1.5	-	-	S
Dynamic							
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$		-	260	-	-
Output Capacitance	C _{oss}			-	77	-	
Reverse Transfer Capacitance	C _{rss}			-	15	-	pF
Drain to Sink Capacitance	С			-	12	-	
Total Gate Charge	Qg		I _D = 4.4 A, V _{DS} = 200 V, see fig. 6 and 13 ^b	-	-	14	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	2.7	
Gate-Drain Charge	Q _{gd}	7		-	-	7.8	
Turn-On Delay Time	t _{d(on)}			-	7.0	-	
Rise Time	t _r	$V_{DD} = 125 \text{ V, } I_D = 4.4 \text{ A,}$ $R_G = 18 \ \Omega, \ R_D = 28 \ \Omega,$ see fig. 10^b		-	13	-	ns
Turn-Off Delay Time	t _{d(off)}			-	20	-	
Fall Time	t _f			-	12	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s			•			
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-		3.4	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	14	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 2.1 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 4.4 A, dl/dt = 100 A/μs ^b		-	200	400	ns
Body Diode Reverse Recovery Charge	Q _{rr}				0.95	1.9	μC
Forward Turn-On Time	t _{on}	Intrinsic to	n-on is dominated by L _S and L _D)				

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

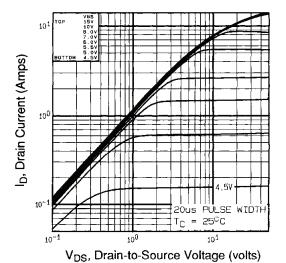


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

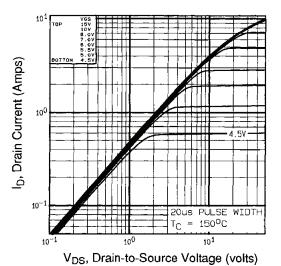


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

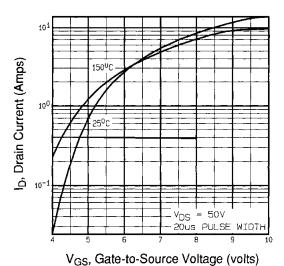


Fig. 3 - Typical Transfer Characteristics

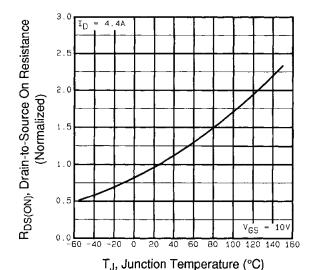
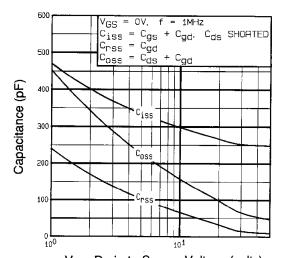
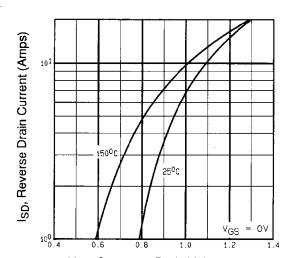


Fig. 4 - Normalized On-Resistance vs. Temperature





V_{DS}, Drain-to-Source Voltage (volts)
Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



V_{SD}, Source-to-Drain Voltage (volts)
Fig. 7 - Typical Source-Drain Diode Forward Voltage

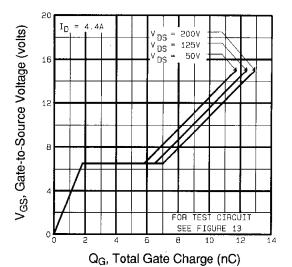
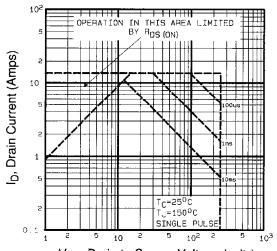


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



V_{DS}, Drain-to-Source Voltage (volts) Fig. 8 - Maximum Safe Operating Area

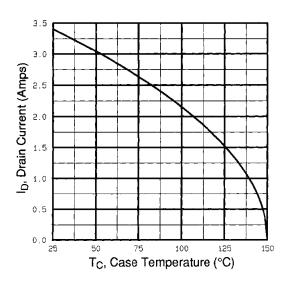


Fig. 9 - Maximum Drain Current vs. Case Temperature

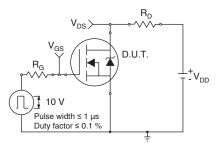


Fig. 10a - Switching Time Test Circuit

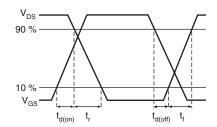


Fig. 10b - Switching Time Waveforms

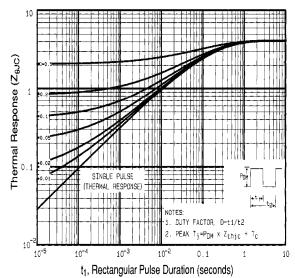


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

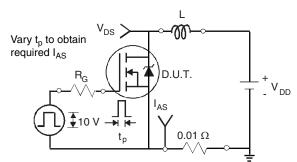


Fig. 12a - Unclamped Inductive Test Circuit

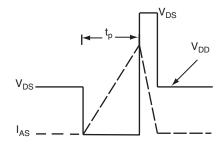


Fig. 12b - Unclamped Inductive Waveforms



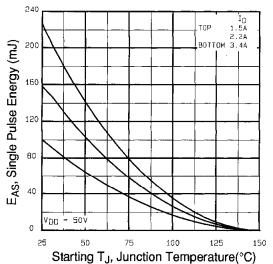


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

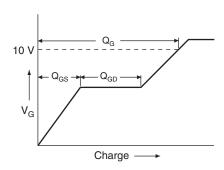


Fig. 13a - Basic Gate Charge Waveform

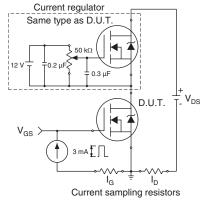
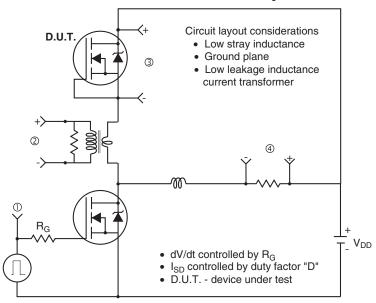
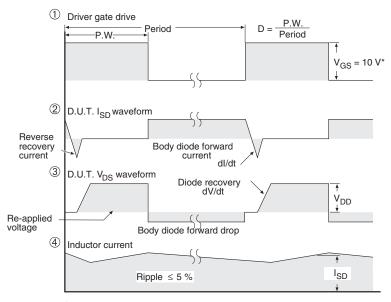


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





 * V_{GS} = 5 V for logic level devices and 3 V drive devices

Fig. 14 - For N-Channel

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